

Notice of References Cited	Application/Control No. 10/767,765	Applicant(s)/Patent Under Reexamination OGAWA, HIDEHIKO	
	Examiner Thomas D. Lee	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,742,769	04-1998	Lee et al.	709/206
	B	US-5,798,845	08-1998	Baek et al.	358/434
	C	US-5,878,230	03-1999	Weber et al.	709/238
	D	US-6,710,894	03-2004	Ogawa, Hidehiko	358/1.15
	E	US-2002/0059362	05-2002	MAEDA, TORU	709/203
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.